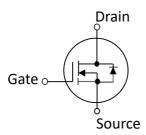


SPQ4RN25WP

25V N-Channel MOSFET

- Advanced Split Gate Device Design and Processes
- High Reliability Capability
- Sampled CP Probing and Inking





Electrical Characteristics in C/P Test (T _J at 25 °C)						
Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
V _{(BR)DSS}	Drain-Source Breakdown Voltage	25	_	_	>	V _{GS} =0V, I _D =250μA
R _{DS(ON)}	Static Drain-Source On-Resistance	_	3.1	4	mΩ	$V_{GS} = 4.5V, I_D = 1A(2)$
V _{GS (th)}	Gate Threshold Voltage	1		2.5	>	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$
I _{DSS}	Drain-to-Source Leakage Current			1	μΑ	V _{DS} =25V, V _{GS} =0V
I _{GSS}	Gate-to-Source Leakage Current	-100	_	100	nA	V _{DS} =0V, V _{GS} =±12V
T _J , T _{STG}	Operating and Storage Temperature		-55°C to 150°C Max.			

Mechanical Data		Die Drawing
Chip Size	1700 μm X 1180 μm	1180um
Gate Pad Size	125 µm X 250 µm	12541
Source Pad Size	844µm X 210 µm	250um
Scribe Line Width	60 µm	
Wafer Thickness	100 μm	210um 210um 210um 210um
Wafer Diameter	200 mm	210um 210um 210um 1700um 1700um
Gross Die	13225 EA	
Source Metallization	Al-Cu (4µm typical)	
Drain Metallization	Ti-Ni-Ag	843.875um 843.875um 843.875um
Passivation	SiN	
Recommended Storage Environment	Store in original container, in dry nitrogen, 6 months at ambient temperature of 23°C ± 3°C	,

- (1) This characteristic assumes the die is assembled in DFN5*6 package. Actual performance may degrade when assembled.
- (2) Pulse Width tp = < 1 mS, Duty Cycle < 2%.

SPQ4RN25WP

Specific Assembly Info	Die Drawing			
Package Type	DFN5*6	1180um		
Die Attach Method	Soft solder	250um		
Soft Solder Composition	Pb,Sn,Ag	4 210um		
Gate Wire Bonding	Cu, 2 mil x1	210um 210um 1700um		
Source Wire Bonding	Cu, 2 mil x12	843		
Molding Compound Manufacturer	G700HF	843.875um 843.875um 843.875um 843.875um		
Solder Plating Composition	Pure Tin			

	Pos	ition	Bonding Diagram Top View
	X (μm)	Υ (μm)	ТОР
ZERO	0	0	sa
TOP	1699.95	1180	57
S1	676.075	100	G2 S5
S2	1519.95	310	G1 54 53
S3	676.075	358	52
S4	1519.95	568	51
S5	676.075	612	ZERO
S6	1519.95	822	
S7	676.075	870	
S8	1519.95	1080	
G1	119.075	465	
G2	244.075	715	



SPQ4RN25WP

Version: 1.0

Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
I _{DSS}	Drain-to-Source Leakage Current	_	_	1	μΑ	V _{DS} =25V, V _{GS} =0V
I _{GSSF}	Gate-to-Source Leakage Current	_	_	100	nA	V _{DS} =0V, V _{GS} =+12V
I _{GSSR}	Gate-to-Source Leakage Current	-100	_	_	nA	V _{DS} =0V, V _{GS} =-12V
BV _{DSS}	Drain-Source Breakdown Voltage	25	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
BV _{DSS}	Drain-Source Breakdown Voltage	25	_	_	V	$V_{GS} = 0V, I_D = 1mA$
R _{DS(ON)}	Static Drain-Source On-Resistance	_	_	6	mΩ	V _{GS} =4.5V, I _D =20A
V _{GS (th)}	Gate Threshold Voltage	1	_	2.5	V	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$
V_{SD}	Body Diode Forward Voltage	_	_	1.1	V	V _{GS} =0V, I _{SD} =10A
I _{AS}	Avalanche Current				А	$\begin{aligned} &V_{\text{DD}}\text{=}25\text{V},V_{\text{GS}}\text{=}10\text{V},\\ &R_{\text{G}}\text{=}25\Omega,L\text{=}0.5\text{mH} \end{aligned}$
T_J , T_{STG}	Operating and Storage Temperature	-55	_	150	°C	

Disclaimer:

JUNSHINE does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

JUNSHINE reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

JUNSHINE makes no warranty, representation or guarantee regarding the suitability of the products for any particular purpose or the continuing production of any product. To the maximum extent permitted by applicable law, JUNSHINE disclaims (1) any and all liability arising out of the application or use of any product, (2) any and all liability, including without limitation special, consequential or incidental damages, and (3) any and all implied warranties, including warranties of fitness for particular purpose, non-infringement and merchantability.

JUNSHINE products, except as expressly indicated in writing, are not designed for use in medical, life-saving, or life-sustaining applications, or for any other application in which the failure of the JUNSHINE product could result in personal injury or death. Customers using or selling JUNSHINE products not expressly indicated for use in such applications do so at their own risks.

Resale of JUNSHINE products with statements different from or beyond the parameters stated by JUNSHINE for that product or service voids all express or implied warrantees for the associated JUNSHINE product or service and is unfair and deceptive business practice. JUNSHINE is not responsible or liable for any such statements.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted by this document or by any conduct of JUNSHINE. Product names and markings noted herein may be trademarks of their respective owners.

JUNSHINE IS A FULLY OWNED SUBSIDIARY OF Wuxi XICHANWEIXIN Semiconductor Co., Ltd.

Address: Floor 5, D2 Building, No. 200, Linghu Blvd., Wuxi, Jiangsu, China